Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/072,939	WEI ET AL.
Examiner	Art Unit
John B. Strege	2625

SEARCHED					
Class	Subclass	Date	Examiner		
382	274,181 190,195 206,299 300,118	11/16/2005	JS		
382	131	11/16/2005	JS		
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INTERFERENCE SEARCHED				
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